

**Search Notes**

Application/Control No.

10/676,025

Examiner

Paul D. Kim

Applicant(s)/Patent under  
Reexamination

YEOM ET AL.

Art Unit

3729

**SEARCHED**

| Class | Subclass                                  | Date      | Examiner |
|-------|---|-----------|----------|
| 29    | 603.03<br>729<br>737<br>757<br>759<br>760 | 6/13/2006 | PK       |
| 360   | 98.07<br>98.0                             |           |          |
|       | 99.08<br>99.1                             |           |          |
| 33    | 568<br>552<br>180                         |           |          |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE      | EXMR |
|--|-----------|------|
| Text Search<br>EAST/NPL (IEEE)                               | 6/13/2006 | PK   |
| Reviewed<br>Relative Application<br>10/676,144<br>10/676,145 | 6/13/2006 | PK   |
| Updated<br>Text Search<br>EAST                               | 6/14/2006 | PK   |
| Updated<br>Text Search<br>EAST                               | 12/5/2006 | PK   |
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